

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10574153	DEYN ET AL.
	Examiner Loewe, Sun Jae Y	Art Unit 1626

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
restriction requirement	10-4-07	sl
restriction requirement	11-9-2007	sl

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner